

Contents

Part I Spectroscopic SPM at the Resolution Limits

- 1 Excitation and Mechanisms of Single Molecule Reactions in Scanning Tunneling Microscopy** 3
Peter Maksymovych
- 2 High-Resolution Architecture and Structural Dynamics of Microbial and Cellular Systems: Insights from in Vitro Atomic Force Microscopy**..... 39
Alexander J. Malkin and Marco Plomp

Part II Dynamic Spectroscopic SPM

- 3 Dynamic Force Microscopy and Spectroscopy in Ambient Conditions: Theory and Applications** 71
Hendrik Hölscher, Jan-Erik Schmutz, and Udo D. Schwarz
- 4 Measuring Mechanical Properties on the Nanoscale with Contact Resonance Force Microscopy Methods**..... 95
D.C. Hurley
- 5 Multi-Frequency Atomic Force Microscopy** 125
Roger Proksch
- 6 Dynamic Nanomechanical Characterization Using Multiple-Frequency Method** 153
Ozgar Sahin

Part III Thermal Characterization by SPM

- 7 Toward Nanoscale Chemical Imaging: The Intersection of Scanning Probe Microscopy and Mass Spectrometry**..... 181
Olga S. Ovchinnikova

8 Dynamic SPM Methods for Local Analysis of Thermo-Mechanical Properties.....	199
M.P. Nikiforov and R. Proksch	

Part IV Electrical and Electromechanical SPM

9 Advancing Characterization of Materials with Atomic Force Microscopy-Based Electric Techniques.....	233
Sergei Magonov, John Alexander, and Shijie Wu	
10 Quantitative Piezoresponse Force Microscopy: Calibrated Experiments, Analytical Theory and Finite Element Modeling.....	301
Lili Tian, Vasudeva Rao Aravind, and Venkatraman Gopalan	
11 High-Speed Piezo Force Microscopy: Novel Observations of Ferroelectric Domain Poling, Nucleation, and Growth	329
Bryan D. Huey and Ramesh Nath	
12 Polar Structures in Relaxors by Piezoresponse Force Microscopy	345
V.V. Shvartsman, W. Kleemann, D.A. Kiselev, I.K. Bdikin, and A.L. Kholkin	
13 Symmetries in Piezoresponse Force Microscopy.....	385
Andreas Ruediger	

Part V Novel SPM Concepts

14 New Capabilities at the Interface of X-Rays and Scanning Tunneling Microscopy	405
Volker Rose, John W. Freeland, and Stephen K. Streiffer	
15 Scanning Ion Conductance Microscopy.....	433
Johannes Rheinlaender and Tilman E. Schäffer	
16 Combined Voltage-Clamp and Atomic Force Microscope for the Study of Membrane Electromechanics.....	461
Arthur Beyder and Frederick Sachs	
17 Dynamic and Spectroscopic Modes and Multivariate Data Analysis in Piezoresponse Force Microscopy	491
B.J. Rodriguez, S.Jesse, K. Seal, N. Balke, S.V. Kalinin, and R. Proksch	

Contents	xiii
18 Polarization Behavior in Thin Film Ferroelectric Capacitors at the Nanoscale	529
A. Gruverman	
Index	541

Scanning Probe Microscopy of Functional Materials

Nanoscale Imaging and Spectroscopy

Kalinin, S.V.; Gruverman, A. (Eds.)

2011, XVIII, 555 p., Hardcover

ISBN: 978-1-4419-6567-7